











CSD19538Q2

SLPS582A - JULY 2016-REVISED JANUARY 2017

# CSD19538Q2 100-V N-Channel NexFET™ Power MOSFET

### **Features**

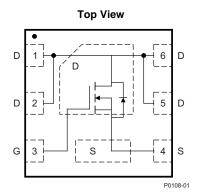
- Ultra-Low Qa and Qad
- Low-Thermal Resistance
- Avalanche Rated
- Lead Free
- **RoHS Compliant**
- Halogen Free
- SON 2-mm × 2-mm Plastic Package

# **Applications**

- Power Over Ethernet (PoE)
- Power Sourcing Equipment (PSE)
- Motor Control

# **Description**

This 100-V, 49-m $\Omega$ , SON 2-mm × 2-mm NexFET<sup>TM</sup> power MOSFET is designed to minimize losses in power conversion applications.



#### **Product Summary**

$T_A = 25^\circ$	С	TYPICAL VA	UNIT	
$V_{DS}$	Drain-to-Source Voltage	100	V	
$Q_g$	Gate Charge Total (10 V)	4.3	nC	
$Q_{gd}$	Gate Charge Gate-to-Drain	0.8		nC
R <sub>DS(on)</sub>	Drain-to-Source On Resistance	V <sub>GS</sub> = 6 V 58		mΩ
	Drain-to-Source On Resistance	V <sub>GS</sub> = 10 V	49	11112
V <sub>GS(th)</sub>	Threshold Voltage	3.2	V	

## **Device Information**<sup>(1)</sup>

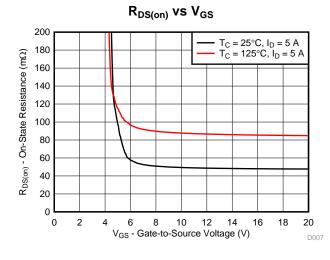
DEVICE	QTY	MEDIA	PACKAGE	SHIP
CSD19538Q2	3000		SON	Tape
CSD19538Q2T	250	7-Inch Reel	2.00-mm x 2.00-mm Plastic Package	and Reel

(1) For all available packages, see the orderable addendum at the end of the data sheet.

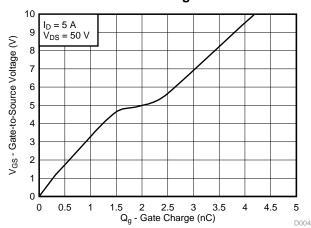
#### **Absolute Maximum Ratings**

T <sub>A</sub> = 2	5°C	VALUE	UNIT	
$V_{DS}$	Drain-to-Source Voltage	100	V	
$V_{\text{GS}}$	Gate-to-Source Voltage	±20	٧	
I <sub>D</sub>	Continuous Drain Current (Package Limited)	14.4		
	Continuous Drain Current (Silicon Limited), $T_C = 25^{\circ}C$	13.1	Α	
	Continuous Drain Current <sup>(1)</sup>	4.6		
$I_{DM}$	Pulsed Drain Current <sup>(2)</sup>	34.4	Α	
<b>D</b>	Power Dissipation <sup>(1)</sup>	2.5	١٨/	
$P_D$	Power Dissipation, T <sub>C</sub> = 25°C	20.2	W	
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction Temperature, Storage Temperature	-55 to 150	ô	
E <sub>AS</sub>	Avalanche Energy, Single Pulse $\rm I_D=12.6~A,L=0.1~mH,R_G=25~\Omega$	8	mJ	

- (1) Typical  $R_{\theta JA} = 50^{\circ}\text{C/W}$  on a 1-in<sup>2</sup>, 2-oz Cu pad on a 0.06-in thick FR4 PCB.
- (2) Max  $R_{\theta,IC} = 6.2$ °C/W, pulse duration  $\leq 100 \mu s$ , duty cycle  $\leq$



#### **Gate Charge**





# **Table of Contents**

1	Features	1	6.1 Receiving Notification of Documentation Updates
2	Applications	1	6.2 Community Resources
3	Description	1	6.3 Trademarks
	Revision History		6.4 Electrostatic Discharge Caution
	Specifications		6.5 Glossary
_	5.1 Electrical Characteristics		7 Mechanical, Packaging, and Orderable
	5.2 Thermal Information	3	Information
	5.3 Typical MOSFET Characteristics	4	7.1 Q2 Package Dimensions
6	Device and Documentation Support	7	7.2 Q2 Tape and Reel Information 1

# 4 Revision History

CI	Changes from Original (July 2016) to Revision A							
•	Changed test voltage V <sub>DS</sub> from 100 V : to 50 V in Gate Charge curve							
•	Changed test voltage V <sub>DS</sub> from 100 V : to 50 V in Figure 4							



# 5 Specifications

#### 5.1 Electrical Characteristics

 $T_{A} = 25^{\circ}C$  (unless otherwise stated)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	CHARACTERISTICS					
BV <sub>DSS</sub>	Drain-to-source voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	100			V
I <sub>DSS</sub>	Drain-to-source leakage current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 80 V			1	μΑ
I <sub>GSS</sub>	Gate-to-source leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V			100	nA
V <sub>GS(th)</sub>	Gate-to-source threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.8	3.2	3.8	V
Б	Danie to come or resistance	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 5 A		58	72	0
R <sub>DS(on)</sub>	Drain-to-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A		49	59	mΩ
9 <sub>fs</sub>	Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 5 A		19		S
DYNAMI	IC CHARACTERISTICS					
C <sub>iss</sub>	Input capacitance			349	454	pF
C <sub>oss</sub>	Output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}$		69	90	pF
C <sub>rss</sub>	Reverse transfer capacitance			12.6	16.4	pF
R <sub>G</sub>	Series gate resistance			4.6	9.2	Ω
Qg	Gate charge total (10 V)			4.3	5.6	nC
Q <sub>gd</sub>	Gate charge gate-to-drain	V 50 V 1 5 A		0.8		nC
Q <sub>gs</sub>	Gate charge gate-to-source	$V_{DS} = 50 \text{ V}, I_{D} = 5 \text{ A}$		1.6		nC
Q <sub>g(th)</sub>	Gate charge at V <sub>th</sub>			1.0		nC
Q <sub>oss</sub>	Output charge	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V		12.3		nC
t <sub>d(on)</sub>	Turnon delay time			5		ns
t <sub>r</sub>	Rise time	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 10 V,		3		ns
t <sub>d(off)</sub>	Turnoff delay time	$I_{DS} = 5 \text{ A}, R_G = 0 \Omega$		7		ns
t <sub>f</sub>	Fall time			2		ns
DIODE C	CHARACTERISTICS					
V <sub>SD</sub>	Diode forward voltage	I <sub>SD</sub> = 5 A, V <sub>GS</sub> = 0 V		0.85	1.0	V
Q <sub>rr</sub>	Reverse recovery charge	V <sub>DS</sub> = 50 V, I <sub>F</sub> = 5 A,		94		nC
t <sub>rr</sub>	Reverse recovery time	di/dt = 300 A/μs		32		ns

## 5.2 Thermal Information

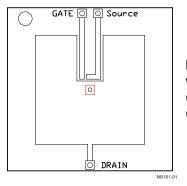
 $T_A = 25$ °C (unless otherwise stated)

	THERMAL METRIC	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-case thermal resistance <sup>(1)</sup>			6.2	°C/W
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)(2)</sup>			65	°C/W

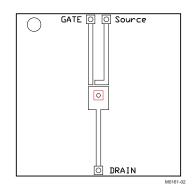
 <sup>(1)</sup> R<sub>θ,JC</sub> is determined with the device mounted on a 1-in² (6.45-cm²), 2-oz (0.071-mm) thick Cu pad on a 1.5-in x 1.5-in (3.81-cm x 3.81-cm), 0.06-in (1.52-mm) thick FR4 PCB. R<sub>θ,JC</sub> is specified by design, whereas R<sub>θ,JA</sub> is determined by the user's board design.
 (2) Device mounted on FR4 material with 1-in² (6.45-cm²), 2-oz (0.071-mm) thick Cu.

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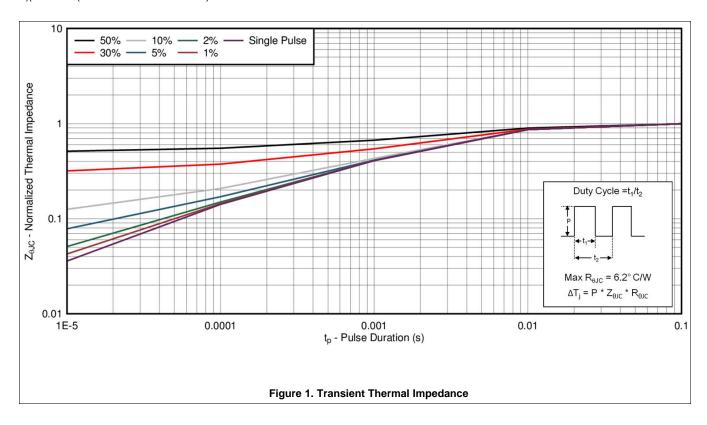
Max  $R_{\theta JA} = 65^{\circ}\text{C/W}$  when mounted on 1 in<sup>2</sup> (6.45 cm<sup>2</sup>) of 2-oz (0.071-mm) thick Cu.



Max  $R_{\theta JA} = 250^{\circ}\text{C/W}$  when mounted on a minimum pad area of 2-oz (0.071-mm) thick Cu.

# 5.3 Typical MOSFET Characteristics

 $T_A = 25$ °C (unless otherwise stated)



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# **Typical MOSFET Characteristics (continued)**

 $T_A = 25$ °C (unless otherwise stated)

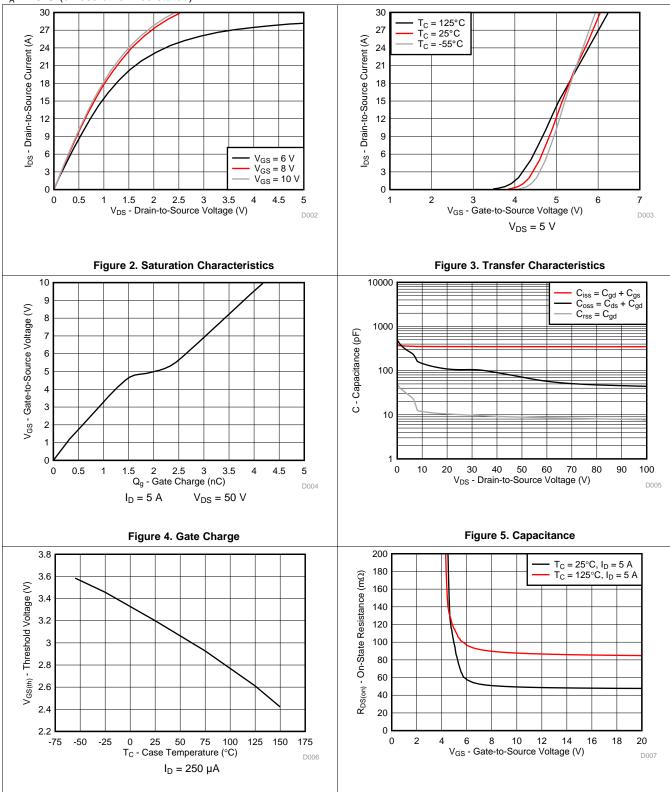


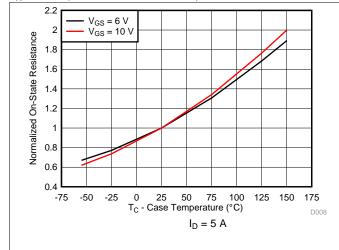
Figure 6. Threshold Voltage vs Temperature

Figure 7. On-State Resistance vs Gate-to-Source Voltage

# TEXAS INSTRUMENTS

# **Typical MOSFET Characteristics (continued)**

 $T_A = 25$ °C (unless otherwise stated)



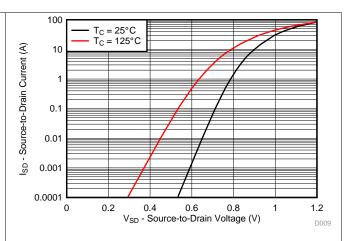
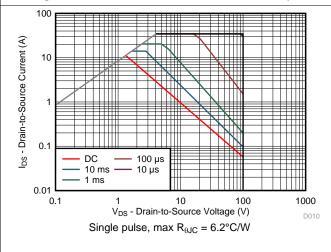


Figure 8. Normalized On-State Resistance vs Temperature





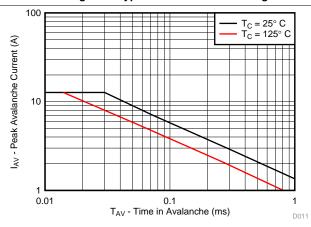


Figure 10. Maximum Safe Operating Area

Figure 11. Single Pulse Unclamped Inductive Switching

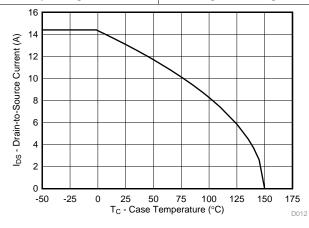


Figure 12. Maximum Drain Current vs Temperature



# 6 Device and Documentation Support

#### 6.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 6.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 6.3 Trademarks

NexFET, E2E are trademarks of Texas Instruments.

All other trademarks are the property of their respective owners.

#### 6.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 6.5 Glossary

SLYZ022 — TI Glossary.

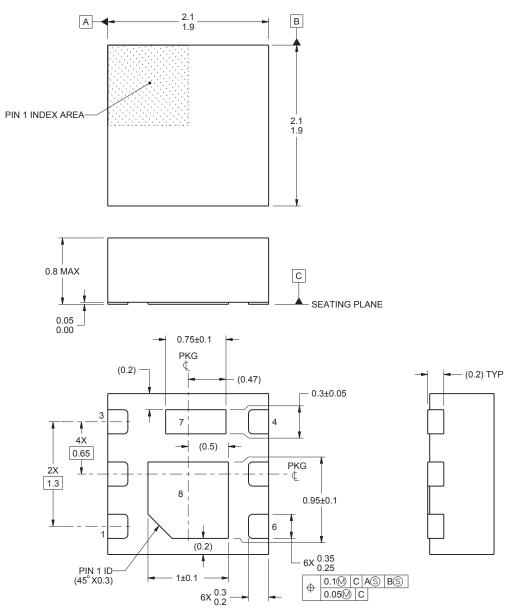
This glossary lists and explains terms, acronyms, and definitions.



# 7 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

#### 7.1 Q2 Package Dimensions



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pads must be soldered to the printed circuit board for thermal and mechanical performance.

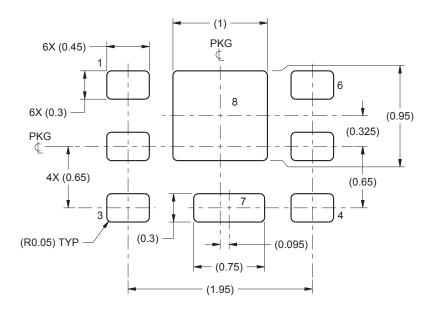
Submit Documentation Feedback

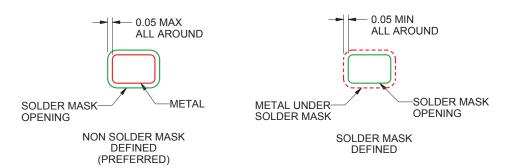
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# **Q2 Package Dimensions (continued)**

#### 7.1.1 Recommended PCB Pattern





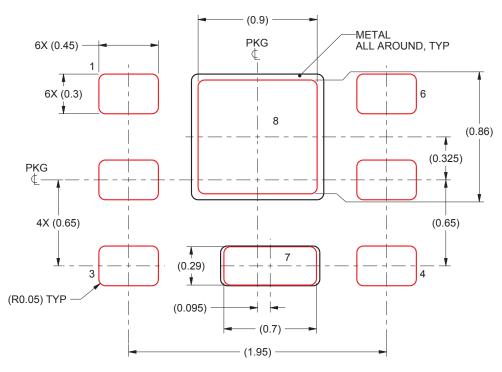
- 1. For recommended circuit layout for PCB designs, see *Reducing Ringing Through PCB Layout Techniques* (SLPA005).
- 2. This package is designed to be soldered to a thermal pad on the board. For more information, see *QFN/SON PCB Attachment* (SLUA271).

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# **Q2 Package Dimensions (continued)**

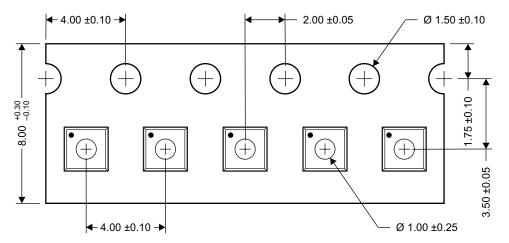
## 7.1.2 Recommended Stencil Pattern

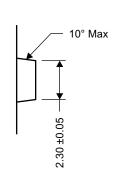


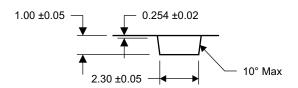
- 1. All linear dimensions are in millimeters.
- 2. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



# 7.2 Q2 Tape and Reel Information







M0168-01

Notes: 1. Measured from centerline of sprocket hole to centerline of pocket.

- 2. Cumulative tolerance of 10 sprocket holes is ±0.2.
- 3. Other material available.
- 4. Typical SR of form tape Max 109 OHM/SQ.
- 5. All dimensions are in mm, unless otherwise specified.

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# PACKAGE OPTION ADDENDUM

10-Dec-2020

#### **PACKAGING INFORMATION**

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD19538Q2	ACTIVE	WSON	DQK	6	3000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-55 to 150	1958	Samples
CSD19538Q2T	ACTIVE	WSON	DQK	6	250	RoHS & Green	SN	Level-1-260C-UNLIM	-55 to 150	1958	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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